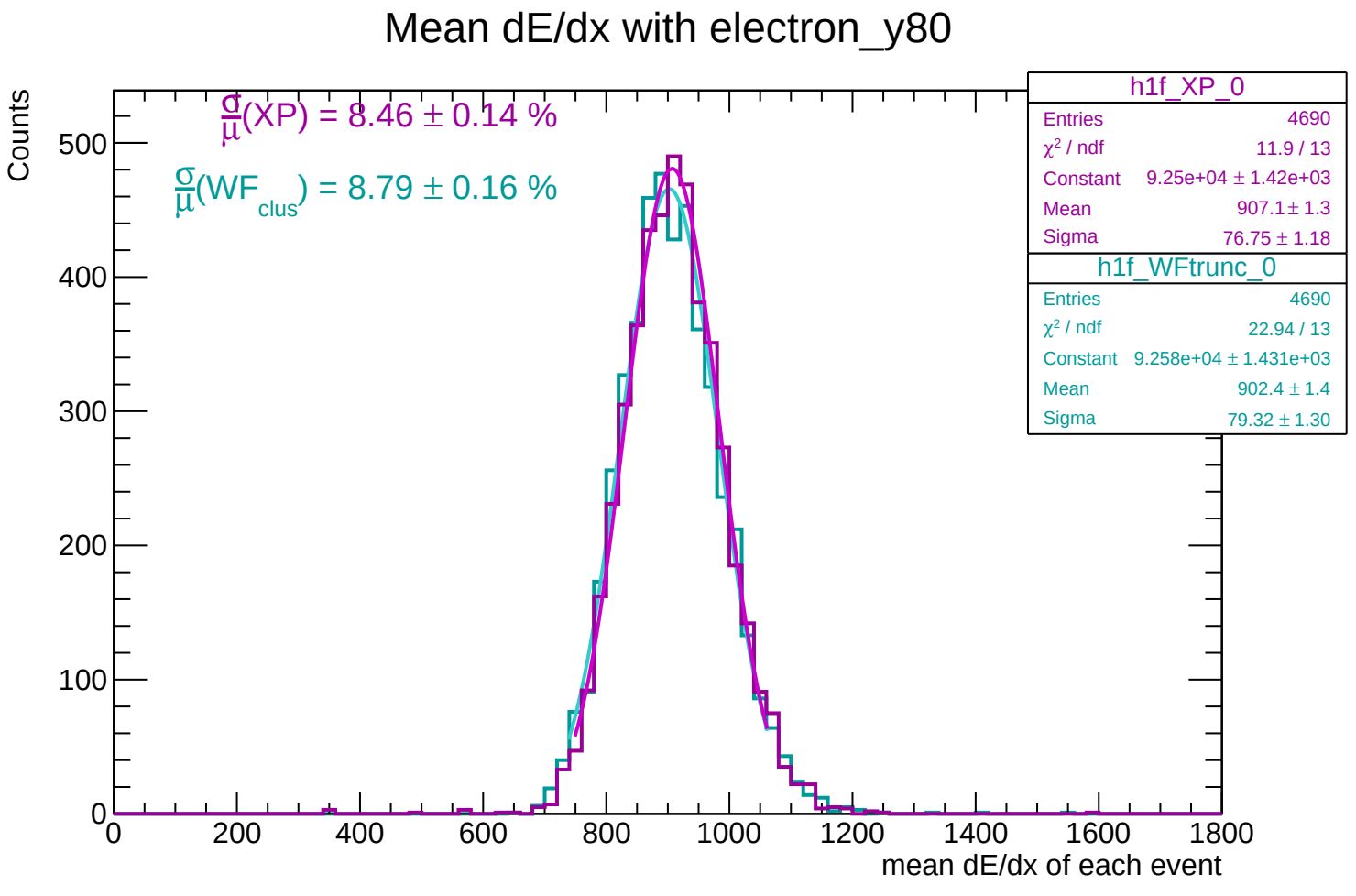
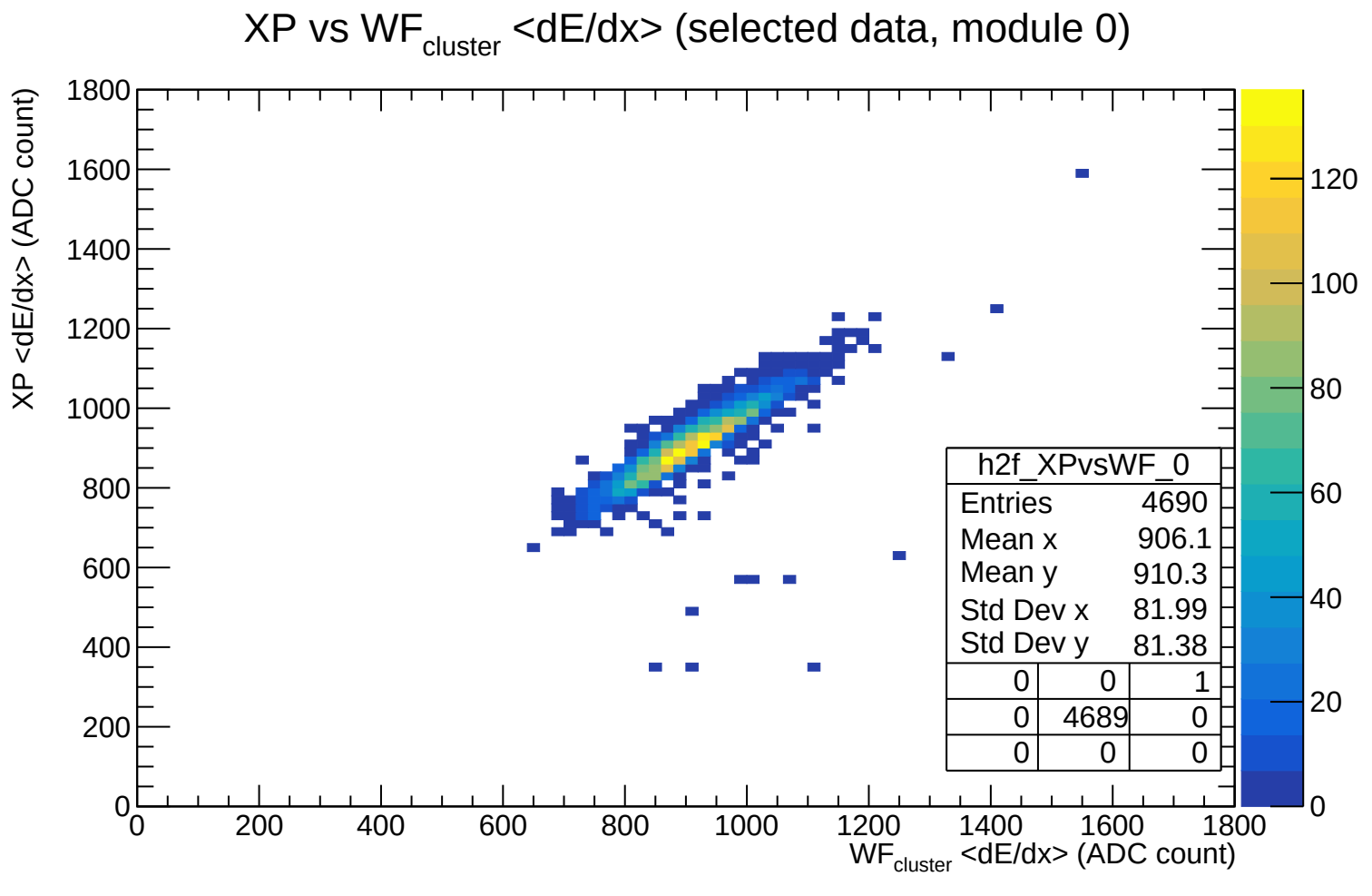
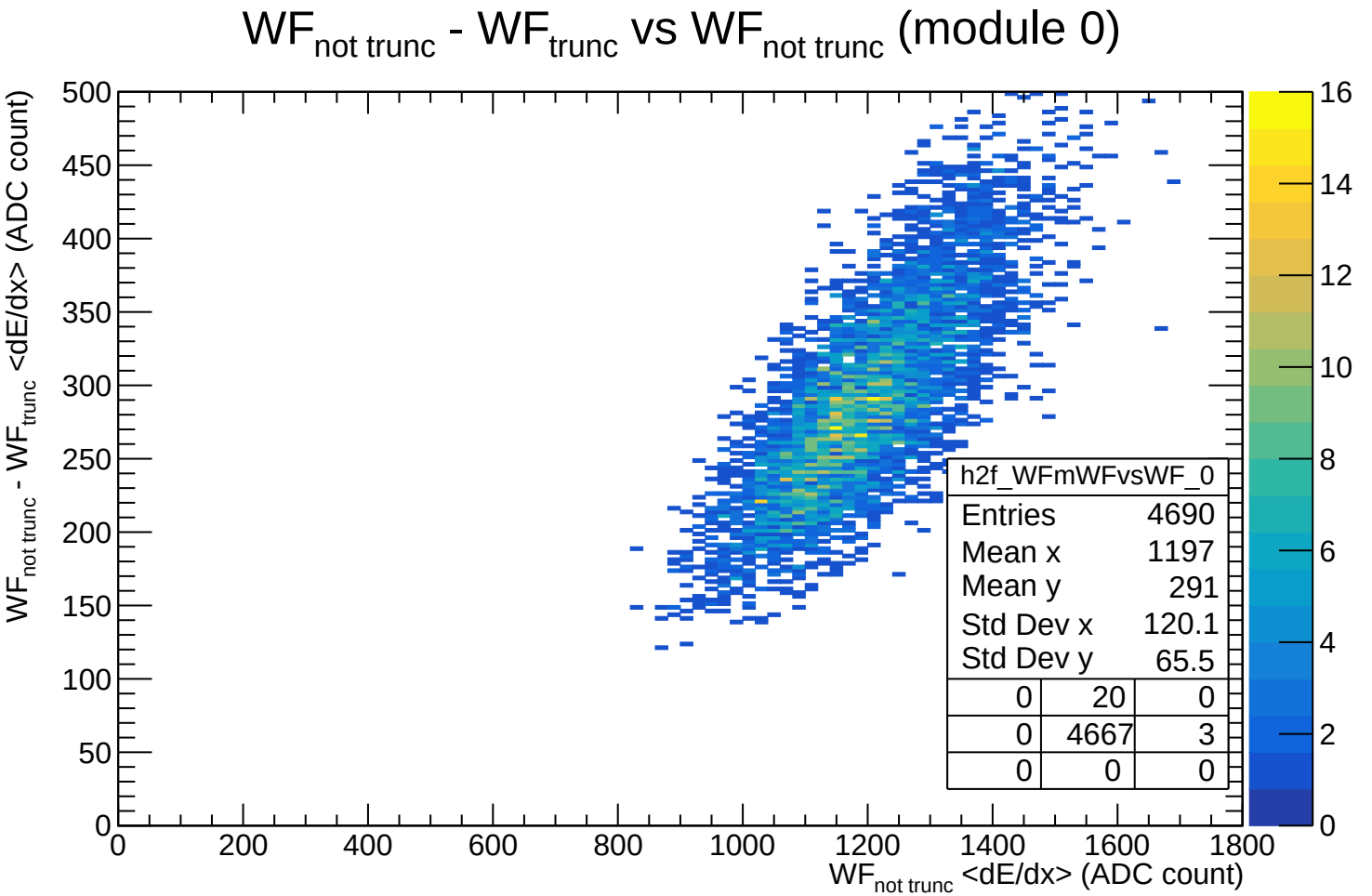

Mean dE/dx with electron_y80
σ/μ(XP) = 8.46 ± 0.14 %
σ/μ(WF_clus) = 8.79 ± 0.16 %
h1f_XP_0
Entries 4690
χ² / ndf 11.9 / 13
Constant 9.25e+04 ± 1.42e+03
Mean 907.1 ± 1.3
Sigma 76.75 ± 1.18
h1f_WFtrunc_0
Entries 4690
χ² / ndf 22.94 / 13
Constant 9.258e+04 ± 1.431e+03
Mean 902.4 ± 1.4
Sigma 79.32 ± 1.30
Counts
0
100
200
300
400
500
0
200
400
600
800
1000
1200
1400
1600
1800
mean dE/dx of each event


XP vs WF_cluster <dE/dx> (selected data, module 0)
XP <dE/dx> (ADC count)
WF_cluster <dE/dx> (ADC count)
h2f_XPvsWF_0
Entries 4690
Mean x 906.1
Mean y 910.3
Std Dev x 81.99
Std Dev y 81.38
0 0 1
0 4689 0
0 0 0


WF not trunc - WF trunc vs WF not trunc (module 0)
WF not trunc - WF trunc <dE/dx> (ADC count)
WF not trunc <dE/dx> (ADC count)
h2f_WFmWFvsWF_0
Entries 4690
Mean x 1197
Mean y 291
Std Dev x 120.1
Std Dev y 65.5
0 20 0
0 4667 3
0 0 0